## Notice of References Cited Application/Control No. 10/682,542 Examiner X. L. Bautista Applicant(s)/Patent Under Reexamination WEE ET AL. Art Unit Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,948,131 B1	09-2005	Neven et al.	715/753
*	В	US-2002/0112004	08-2002	Reid et al.	709/205
*	C	US-2002/0106998	08-2002	Presley et al.	455/403
	D	US-			
	Ε	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2003-224836	08-2003	Japan	Toshikazu KANEKO	H04M 7/15
	0					
	Р					
	Q					
	R					
	s					
	T					

## NON-PATENT DOCUMENTS

	NOTE A POSSIBLE OF					
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
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	V					
	w					
	x					

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

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